

75N75**Power MOSFET**

75Amps, 75Volts
N-CHANNEL POWER MOSTFET

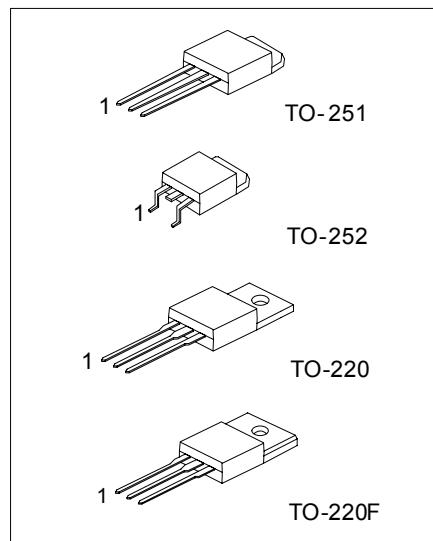
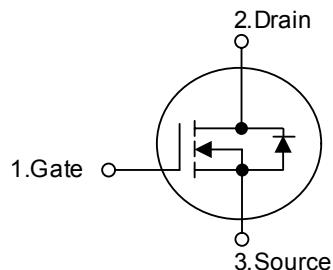
■ DESCRIPTION

The UTC **75N75** is n-channel enhancement mode power field effect transistors with stable off-state characteristics, fast switching speed, low thermal resistance, usually used at telecom and computer application.

■ FEATURES

- * $R_{DS(ON)} = 12.5\text{m}\Omega$ @ $V_{GS} = 10\text{ V}$
- * Ultra low gate charge (typical 90 nC)
- * Fast switching capability
- * Avalanche energy Specified
- * Improved dv/dt capability, high ruggedness

■ SYMBOL



*Pb-free plating product number: 75N75L

■ ORDERING INFORMATION

Order Number		Package	Pin Assignment			Packing
Normal	Lead Free Plating		1	2	3	
75N75-TA3-T	75N75L-TA3-T	TO-220	G	D	S	Tube
75N75-TF3-T	75N75L-TF3-T	TO-220F	G	D	S	Tube
75N75-TM3-T	75N75L-TM3-T	TO-251	G	D	S	Tube
75N75-TN3-R	75N75L-TN3-R	TO-252	G	D	S	Tape Reel
75N75-TN3-T	75N75L-TN3-T	TO-252	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

	(1) T: Tube, R: Tape Reel (2) TA3: TO-220, TF3: TO-220F, TM3: TO-251, TN3: TO-252 (3) L: Lead Free Plating Blank: Pb/Sn
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■ ELECTRICAL CHARACTERISTICS(Cont.)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Source-Drain Diode Ratings and Characteristics						
Continuous Source Current	I _S			75		A
Pulsed Source Current	I _{SM}			300		
Diode Forward Voltage	V _{SD}	I _S = 48A, V _{GS} = 0 V		1.4		V
Reverse Recovery Time	t _{rr}	I _S = 48A, V _{GS} = 0 V dI _F / dt = 100 A/μs	90			ns
Reverse Recovery Charge	Q _{rr}		300			μC

Note 1. Repeatability rating: pulse width limited by junction temperature

2. L=0.24mH, I_{AS}=48A, R_G=20Ω, Starting T_J=25
3. I_{SD}≤48A, di/dt≤300A/μs, V_{DD}≤BV_{DSS}, Starting T_J=25
4. Pulse Test: Pulse Width≤300μs,Duty Cycle≤2%
5. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

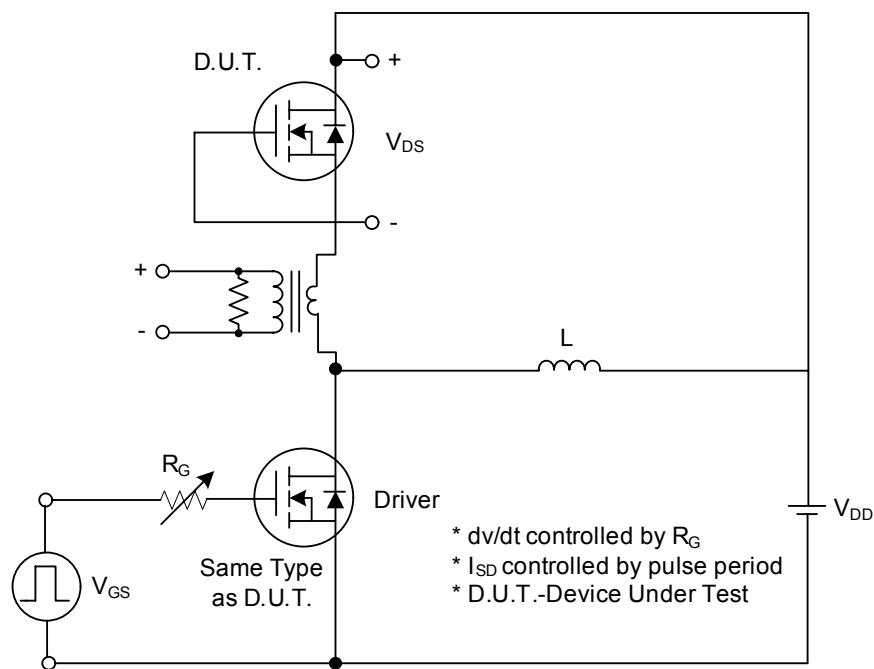


Fig. 1A Peak Diode Recovery dv/dt Test Circuit

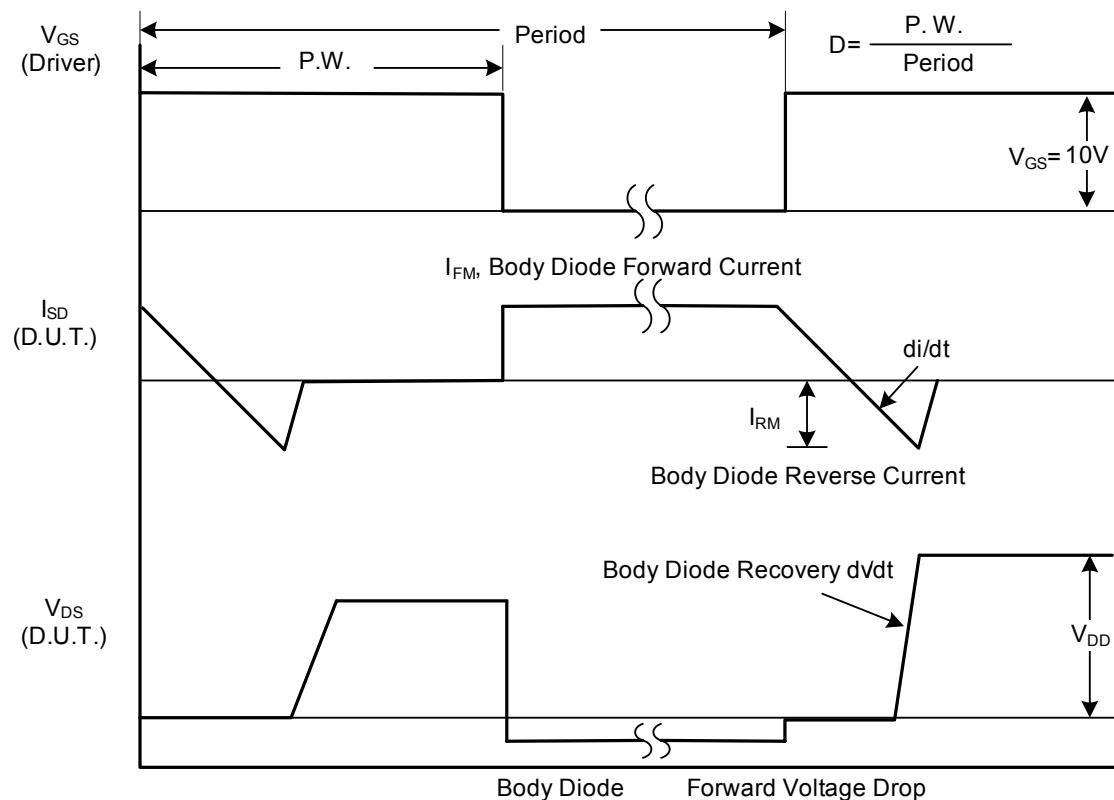


Fig. 1B Peak Diode Recovery dv/dt Waveforms

■ TEST CIRCUITS AND WAVEFORMS (Cont.)

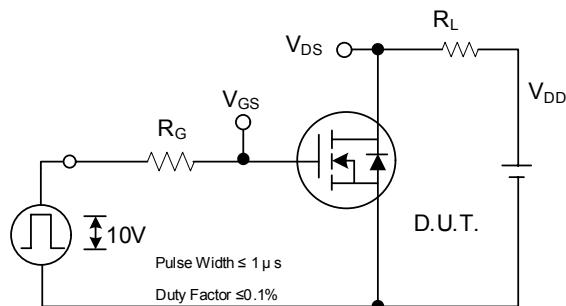


Fig. 2A Switching Test Circuit

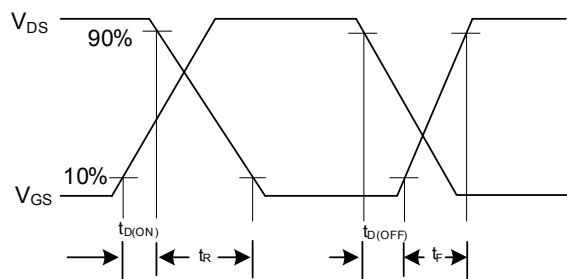


Fig. 2B Switching Waveforms

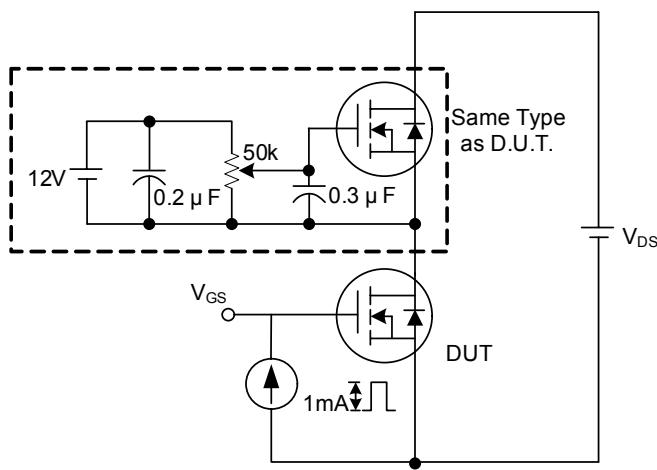


Fig. 3A Gate Charge Test Circuit

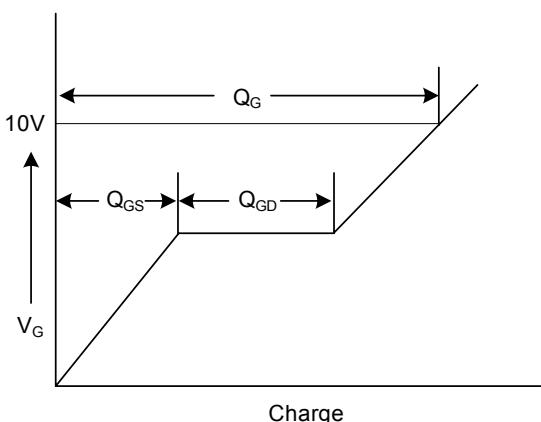


Fig. 3B Gate Charge Waveform

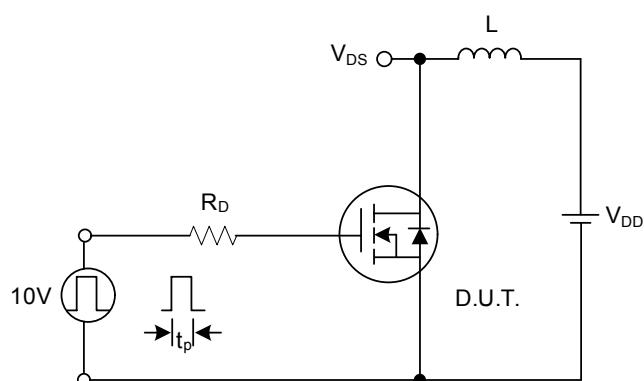


Fig. 4A Unclamped Inductive Switching Test Circuit

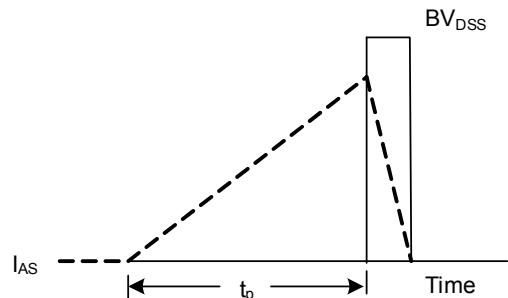
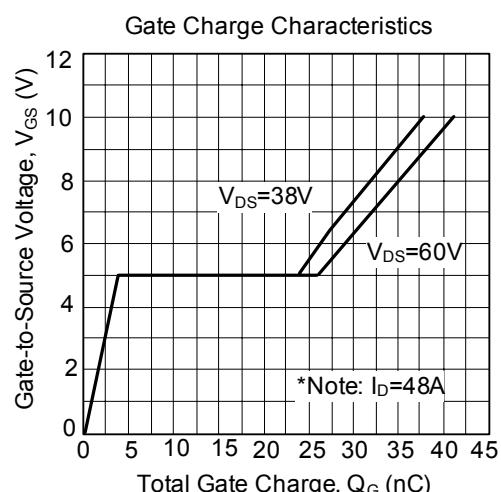
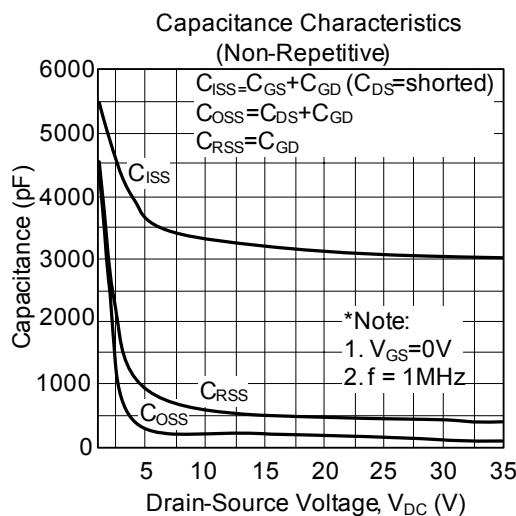
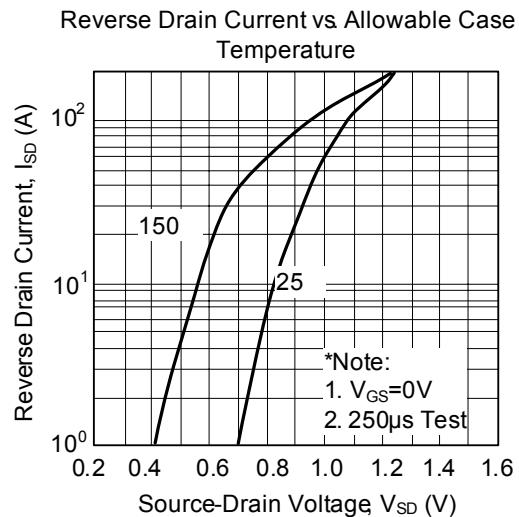
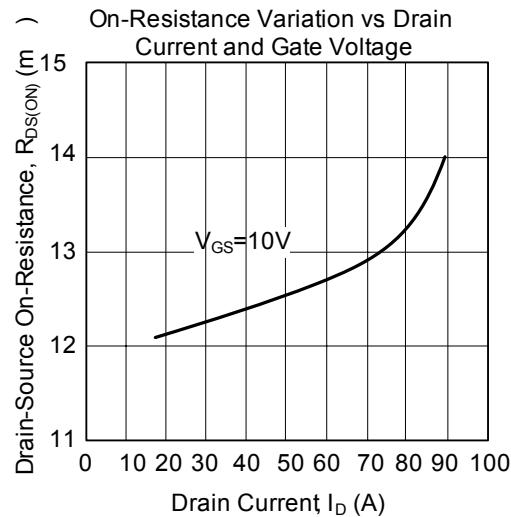
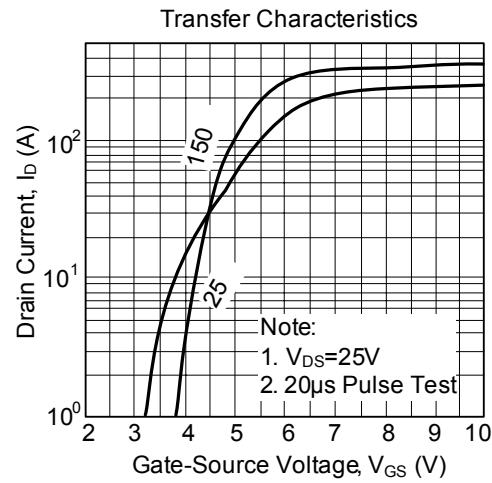
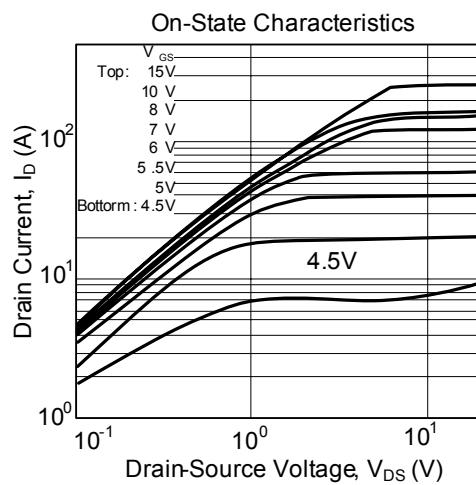
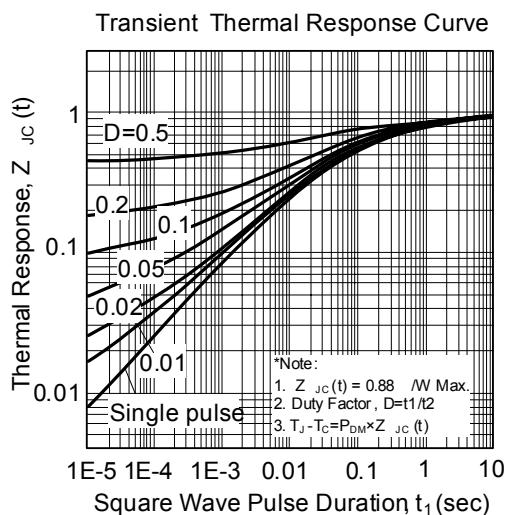
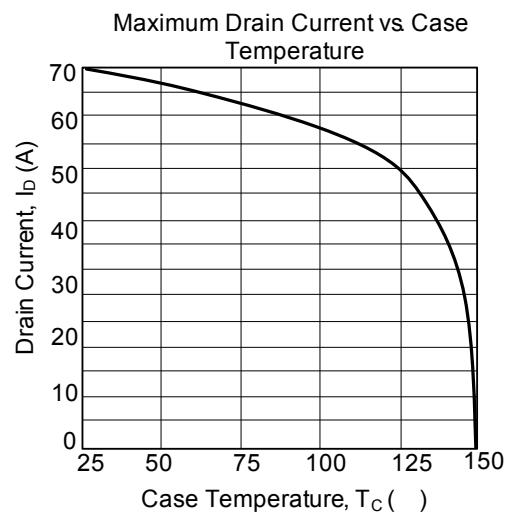
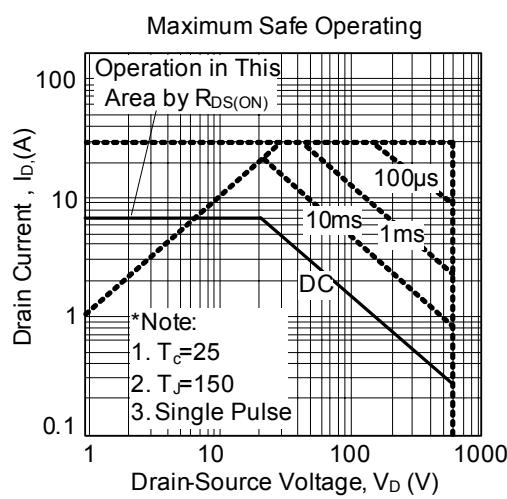
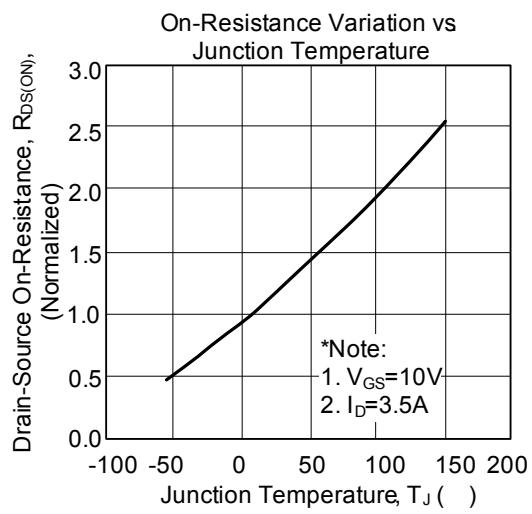
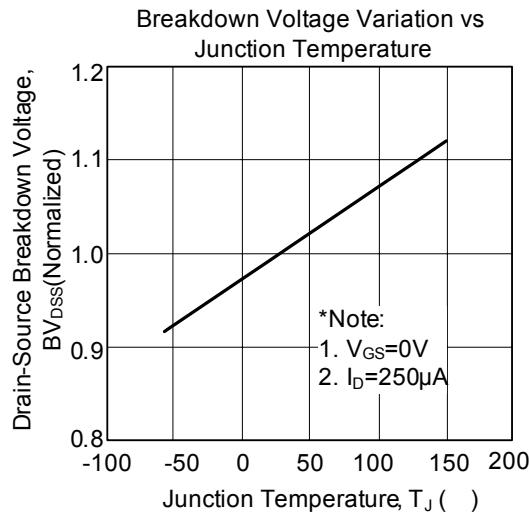


Fig. 4B Unclamped Inductive Switching Waveforms

■ TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS(Cont.)



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